

MS20N04NE N-Channel 20V (D-S) MOSFET

General Description

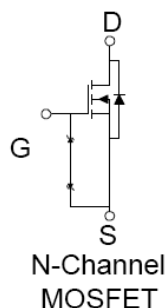
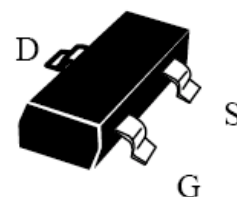
These miniature surface mount MOSFETs utilize High Cell Density process. Low $r_{DS(on)}$ assures minimal power loss and conserves energy, making this device ideal for use in power management circuitry. Typical applications are PWMDC-DC converters, power management in portable and battery-powered products such as computers, printers, battery charger, telecommunication power system, and telephones power system.

FEATURES

- Low $r_{DS(on)}$ Provides Higher Efficiency and
- Extends Battery Life
- Miniature SOT-23 Surface Mount Package
- Saves Board Space
- High power and current handling capability
- Low side high current DC-DC Converter
- Applications

MAXIMUM RATINGS AND ELECTRICAL CHARACTERISTICS

SOT-23-3L



ESD Protected

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)				
Parameter		Symbol	Maximum	Units
Drain-Source Voltage		V_{DS}	20	V
Gate-Source Voltage		V_{GS}	± 12	
Continuous Drain Current ^a	$T_A = 25^\circ\text{C}$	I_D	4.0	A
	$T_A = 70^\circ\text{C}$		3.1	
Pulsed Drain Current ^b		I_{DM}	± 20	
Continuous Source Current (Diode Conduction) ^a		I_S	1.6	A
Power Dissipation ^a	$T_A = 25^\circ\text{C}$	P_D	1.3	W
	$T_A = 70^\circ\text{C}$		0.8	
Operating Junction and Storage Temperature Range		T_J, T_{stg}	-55 to 150	$^\circ\text{C}$

THERMAL RESISTANCE RATINGS				
Parameter		Symbol	Maximum	Units
Maximum Junction-to-Ambient ^a	$t \leq 5 \text{ sec}$	R_{THJA}	100	$^\circ\text{C/W}$
	Steady-State		166	

Notes

- a. Surface Mounted on 1" x 1" FR4 Board.
- b. Pulse width limited by maximum junction temperature

SPECIFICATIONS ($T_A = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)						
Parameter	Symbol	Test Conditions	Limits			Unit
			Min	Typ	Max	
Static						
Gate-Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	0.7			V
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 8 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 16 \text{ V}, V_{GS} = 0 \text{ V}$			1	uA
		$V_{DS} = 16 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55^\circ\text{C}$			10	
On-State Drain Current ^A	$I_{D(on)}$	$V_{DS} = 5 \text{ V}, V_{GS} = 4.5 \text{ V}$	10			A
Drain-Source On-Resistance ^A	$r_{DS(on)}$	$V_{GS} = 4.5 \text{ V}, I_D = 4.6 \text{ A}$			32	m Ω
		$V_{GS} = 2.5 \text{ V}, I_D = 3.9 \text{ A}$			44	
Forward Transconductance ^A	g_{fs}	$V_{DS} = 10 \text{ V}, I_D = 4.0 \text{ A}$		11.3		S
Diode Forward Voltage	V_{SD}	$I_S = 1.6 \text{ A}, V_{GS} = 0 \text{ V}$		0.75		V
Dynamic^b						
Total Gate Charge	Q_g	$V_{DS} = 10 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 4.0 \text{ A}$		13.4		nC
Gate-Source Charge	Q_{gs}			0.9		
Gate-Drain Charge	Q_{gd}			2.0		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 10 \text{ V}, R_L = 15 \Omega, I_D = 1 \text{ A}, V_{GEN} = 4.5 \text{ V}$		8		ns
Rise Time	t_r			24		
Turn-Off Delay Time	$t_{d(off)}$			35		
Fall-Time	t_f			10		
Source-Drain Reverse Recovery Time	t_{rr}	$I_F = 1.6 \text{ A}, di/dt = 100 \text{ A/uS}$		40		

Notes

- a. Pulse test: PW $\leq 300\mu\text{s}$ duty cycle $\leq 2\%$.
- b. Guaranteed by design, not subject to production testing.